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APPLICATION NO.	FI	LING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/079,475	C	02/19/2002	Spencer Gold	SMQ-089/P6550	6691	
959	7590	10/03/2003		EXAM	EXAMINER	
LAHIVE &		IELD	SUN, X	SUN, XIUQIN		
28 STATE STREET BOSTON, MA 02109				ART UNIT	PAPER NUMBER	
,				2863		

DATE MAILED: 10/03/2003

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)	•••					
		10/079,475	GOLD ET AL.						
	Office Action Summary	Examiner	Art Unit						
		Xiuqin Sun	2863						
Period fo	 The MAILING DATE of this communicater 	ion appears on the cover sheet	with the correspondence addres	s					
A SHO THE N - Exten- after S - If the - If NO - Failure - Any re	DRTENED STATUTORY PERIOD FOR MAILING DATE OF THIS COMMUNICA' sions of time may be available under the provisions of 37 61X (6) MONTHS from the mailing date of this communication of the provision of the provisio	TION. 'CFR 1.136(a). In no event, however, may ation. ys, a reply within the statutory minimum of y period will apply and will expire SIX (6) M by statute, cause the application to become	a reply be timely filed thirty (30) days will be considered timely. IONTHS from the mailing date of this communication (35 U.S.C. § 133).	nication.					
1)	Responsive to communication(s) filed of	nn.	·						
2a)☐	,	☐ This action is non-final.							
3)□	Since this application is in condition for		natters, prosecution as to the me	erits is					
, —	closed in accordance with the practice on of Claims								
4)🛛	Claim(s) <u>1-38</u> is/are pending in the app	lication.							
	la) Of the above claim(s) is/are w	vithdrawn from consideration.							
5)	Claim(s)is/are allowed.								
6)⊠	Claim(s) <u>1-6,9-13,16-17 and 28-38</u> is/are rejected.								
7)🛛	Claim(s) <u>7,8,14,15 and 18-27</u> is/are objected to.								
8) 🔲	Claim(s) are subject to restriction	and/or election requirement.							
Application	on Papers								
, —	he specification is objected to by the Ex								
10)□ T	he drawing(s) filed on is/are: a)[☐ accepted or b)☐ objected to b	y the Examiner.						
	Applicant may not request that any objection								
11)∐ T	he proposed drawing correction filed on		disapproved by the Examiner.						
40) 🗔 🖚	If approved, corrected drawings are require	• •							
<i>'</i> —	he oath or declaration is objected to by	tne Examiner.							
	nder 35 U.S.C. §§ 119 and 120								
, —	Acknowledgment is made of a claim for	foreign priority under 35 U.S.C	C. § 119(a)-(d) or (f).						
a)[_] All b) ☐ Some * c) ☐ None of:								
•	1. Certified copies of the priority documents have been received.								
•	2. Certified copies of the priority doc		• • • • • • • • • • • • • • • • • • • •						
	3. Copies of the certified copies of the application from the Internation application for the action for the	nal Bureau (PCT Rule 17.2(a)).	е					
	cknowledgment is made of a claim for de	·		lication).					
a)	☐ The translation of the foreign langua	nge provisional application has	been received.	,					
ام اسارة Attachment	cknowledgment is made of a claim for d	omesuc phonty under 35 0.5.	0. 33 120 and/01 121.						
1) 🔏 Notice 2) 🔲 Notice	of References Cited (PTO-892) of Draftsperson's Patent Drawing Review (PTO-9 ation Disclosure Statement(s) (PTO-1449) Paper	948) 5) Notice	w Summary (PTO-413) Paper No(s) of Informal Patent Application (PTO-152						

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DETAILED ACTION

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.
- 2. Claims 30, 31 and 35, 36, 38 are rejected under 35 U.S.C. 102(e) as being anticipated by Miller et al. (U.S. Pat. No. 6542846).

Miller et al. teach a controller and method for monitoring a temperature of an integrated circuit (see Abstract), comprising the steps and means of: receiving a plurality of first values representative of a temperature of said integrated circuit (col. 4, lines 1-28 and col.4, lines 37-51); comparing said plurality of first values to a plurality of corresponding second values representative of a plurality of threshold temperatures (col.9, lines 9 and col. 10, lines 1-4); determining whether an over-temperature condition of said integrated circuit exists based on an output of said means and step for comparing (Fig. 5 and col.9, lines 9 and col. 10, lines 1-4). Miller et al. further teach: steps and means for determining a response to said over-temperature condition (col.

10, lines 5-30) and executing said response to said over-temperature condition (col. 10, lines 5-30).

Claim Rejections - 35 USC § 103

- 3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 4. Claim 1 is rejected under 35 U.S.C. 103(a) as being unpatentable over Miller et al. (U.S. Pat. No. 6542846) in view of Gunther et al. (U.S. Pub. No. 2001/0021217).

Miller et al. teach a controller for monitoring a temperature of an integrated circuit (see Abstract), comprising: a first interface for receiving a first value representative of a temperature of said integrated circuit, the first value is produced by one of an active thermal sensor and a passive thermal sensor formed in said integrated circuit (col. 4, lines 1-28 and col.4, lines 37-51); a second interface for receiving a second value representative of a threshold temperature (col.9, lines 9 and col. 10, lines 1-4); and a comparator for comparing said first value to said second value for determining whether said first value exceeds said second value, thereby determining if said first value indicates an excessive temperature of said integrated circuit (Fig. 5 and col.9, lines 9 and col. 10, lines 1-4).

Miller et al. do not mention: said first value is produced by an active thermal sensor formed in said integrated circuit.

Gunther et al. teach an integrated on-chip thermal management system, wherein an active thermal sensor formed in an integrated circuit is used to sense the temperature of said integrated circuit (sections 0027-0029).

It would have been obvious to one having ordinary skill in the art at the time the invention was made to include the teaching of Gunther et al. in the system of Miller et al. in order to actively monitor the die temperature across said integrated circuit (Miller et al., section 0029).

5. Claims 2-5, 9, 11, 13 and 16 are rejected under 35 U.S.C. 103(a) as being unpatentable over Miller et al. (U.S. Pat. No. 6542846) in view of Gunther et al., as applied to claim 1 above, and further in view of McMinn (U.S. Pat. No. 6098030).

Miller et a. and Gunther et al. teach a system and method that includes the subject matter discussed above. Gunther et al. further teach: a serial temperature capture device for receiving a plurality of temperatures of said integrated circuit, wherein said serial temperature capture device is adapted to receive a plurality of temperatures from a plurality of thermal sensors (sections 0033, 0051 and 0052).

Miller et al. and Gunther et al. do not state explicitly that: said controller further comprises a temperature measurement buffer for holding said first value received from said first interface; sequentially providing said plurality of temperatures of said integrated circuit to said temperature measurement buffer; a threshold buffer corresponding to said temperature measurement buffer and adapted to store a second value representative of a threshold temperature; a microprocessor adapted to communicate with said temperature measurement buffer to read said first value and

thermally profile said integrated circuit; a plurality of temperature measurement buffers, wherein each temperature measurement buffer is adapted to receive a value representative of a temperature of an integrated circuit; a serial temperature capture device for receiving a plurality of temperatures of said integrated circuit and providing said plurality of temperatures of said integrated circuit to said plurality of temperature measurement buffers.

McMinn discloses a thermal management system for an operating integrated circuit (see Abstract), and teaches a controller comprising: a temperature measurement buffer for holding said first value received from said first interface (col. 4, lines 47-54; col. 5, lines 41-56 and col. 6, lines 47-67); a threshold buffer corresponding to said temperature measurement buffer and adapted to store a second value representative of a threshold temperature (col. 4, lines 47-54 and col. 7, lines 37-44); a microprocessor adapted to communicate with said temperature measurement buffer to read said first value and thermally profile said integrated circuit (col. 3, lines 1-7, lines 25-30; and col. 4. lines 35-46); a serial temperature capture device for receiving a plurality of temperatures of said integrated circuit and sequentially providing said plurality of temperatures of said integrated circuit to said temperature measurement buffer (col. 4, line 55 to col. 5, line 23); a plurality of temperature measurement buffers, wherein each temperature measurement buffer is adapted to receive a value representative of a temperature of an integrated circuit (Figs. 1-3; col. 4, line 55 to col. 5, line 23); a serial temperature capture device for receiving a plurality of temperatures of said integrated

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circuit and providing said plurality of temperatures of said integrated circuit to said plurality of temperature measurement buffers (Figs. 1-3; col. 4, line 55 to col. 5, line 23).

It would have been obvious to one having ordinary skill in the art at the time the invention was made to include the teaching of McMinn in the combination of Miller et al. and Gunther et al. in order to provide a control circuit to thermally profile said integrated circuit in which both said temperature measurements and said threshold temperatures are programmable (McMinn, col. 3, lines 1-46).

6. Claim 17 is rejected under 35 U.S.C. 103(a) as being unpatentable over Miller et al. in view of Gunther et al., and further in view of McMinn as applied to claims 1 and 11 above, and further in view of Pricer et al. (U.S. Pat. No. 5873053).

Miller et al., Gunther et al. and McMinn teach a system that includes the subject matter discussed above. The combination of Miller et al., Gunther et al. and McMinn do not mention explicitly that: a plurality of threshold buffers corresponding to said plurality of temperature measurement buffers and adapted to store a plurality of second values representative of threshold temperatures.

Pricer et al. teach on-chip temperature sensors for control of chip operating temperature, wherein said sensors are capable of detecting undesirable temperature condition at different portion of said chip (col. 8, lines 7-26), and a threshold value is determined for each of said thermal sensor based on a location of said thermal sensor in said chip (col. 10, lines 27-38 and col. 11, lines 14-31).

It would have been obvious to one having ordinary skill in the art at the time the invention was made to include the teaching of Pricer et al. in the combination of Miller et

al., Gunther et al. and McMinn to have a plurality of McMinn threshold buffers for storing a plurality of threshold temperatures, in order to provide a thermal management system which can detect any undesirable temperature condition at different portion of the integrated circuit (Pricer et al., Abstract; col. 8, lines 18-26 and col. 10, lines 27-38).

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7. Claims 6, 10, 12 and 28 are rejected under 35 U.S.C. 103(a) as being unpatentable over Miller et al. in view of Gunther et al., and further in view of McMinn as applied to claims 1-5 and 11 above, and further in view of Senyk (U.S. Pat. No. 6363490) and Ristic et al. (U.S. Pat. No. 5291607).

Miller et al., Gunther et al. and McMinn teach a system and method that includes the subject matter discussed above. The combination of Miller et al., Gunther et al. and McMinn do not mention explicitly that: said threshold buffer is located external to said controller; at least one of said plurality of temperature measurement buffers is located external to said controller; an interface from said first interface to a microprocessor to enable said microprocessor to read said first interface.

Senyk discloses a method and apparatus for monitoring the temperature of a processor, and teaches a controller that compares the temperature of the processor to a threshold, wherein said threshold is set by a buffer located external to said controller (col. 4, lines 32-42). Senyk further teaches that: a temperature sensing diode is located external to said controller.

It would have been obvious to one having ordinary skill in the art at the time the invention was made to include the teaching of Senyk threshold buffer in the combination of Miller et al., Gunther et al. and McMinn in order to separate the controller from the

sensed environment so that the performance of the controller is not affected by any undesirable temperature condition of the sensed environment (Ristic et al., col. 1, lines 31-67).

It would also have been obvious to one having ordinary skill in the art at the time the invention was made to apply the teaching of Senyk arrangement for thermal sensor and controller to the combination of Miller et al., Gunther et al. and McMinn such that at least one of said temperature measurement buffers taught by McMinn is located external to said controller, in order to separate the controller from the thermal sensors so that the performance of the controller is not affected by any undesirable temperature condition of the sensed environment (Ristic et al., col. 1, lines 31-67).

Ristic et al. teach an interface to a microprocessor to enable said microprocessor to read output signals from a plurality of sensor cells (Fig. 1; col. 3, lines 21-32, lines 40-50 and col. 4, lines 50-63).

It would have been obvious to one having ordinary skill in the art at the time the invention was made to apply the teaching of Ristic et al. to the Miller et al. processor in order to utilize said microprocessor to process data generated by said sensor cells (Ristic et al., col. 31-67).

8. Claim 29 is rejected under 35 U.S.C. 103(a) as being unpatentable over Miller et al. in view of Gunther et al., as applied to claim 1 above, and further in view of Pippin (U.S. Pat. No. 5838578).

Miller et al. and Gunther et al. teach a system and method that includes the subject matter discussed above. The combination of Miller et al. and Gunther et al. do

not mention explicitly that: said controller further comprises an interface from said second interface to a microprocessor to enable said microprocessor to write to said second interface.

Pippin discloses a method and apparatus for programmable thermal sensor for an integrated circuit, and teaches a controller that comprises an interface to a microprocessor to enable said microprocessor to reset a threshold temperature (Fig. 9; and col. 13, lines 51-67).

It would have been obvious to one having ordinary skill in the art at the time the invention was made to include the teachings of Pippin in the combination of Miller et al. and Gunther et al. system in order to reset dynamically the threshold temperature for thermal management of said integrated circuit (Pippin, Abstract).

9. Claims 32 and 37 are rejected under 35 U.S.C. 103(a) as being unpatentable over Miller et al., as applied to claims 30 and 35 above, and in view of Gunther et al.

Miller et al. teach a system and method that includes the subject matter discussed above. Miller et al. do not mention explicitly that: digitally filtering said output of said means for comparing before determining whether an over-temperature condition of said integrated circuit exists (sections 0035-0038 and 0050);

Gunther et al. teach the step and means of digitally filtering the output of a thermal sensor before determining whether an over-temperature condition of an integrated circuit exists (sections 0035-0038 and 0050);

It would have been obvious to one having ordinary skill in the art at the time the invention was made to include the teaching of Gunther et al. in the Miller et al. system in order to dampen out or remove spurious signals (Gunther et al., section 0036).

10. Claims 33 and 34 are rejected under 35 U.S.C. 103(a) as being unpatentable over Miller et al., as applied to claims 30 above, and further in view of Ristic et al. (U.S. Pat. No. 5291607).

Miller et al. teach a system and method that includes the subject matter discussed above. Miller et al. do not mention explicitly that: a microprocessor capable of reading said means for receiving a plurality of first values and communicating with said means for determining whether an over-temperature condition of said integrated circuit exists; and said microprocessor is capable of writing to said means for receiving a plurality of first values and verifies correct functioning of the controller.

Ristic et al. disclose a microprocessor having environmental sensing capability, and teach that: said microprocessor is capable of reading a plurality of first values representative of the sensed environment, and communicating with means for determining whether an undesirable condition of said environment exists (Fig. 1; col. 3, lines 21-32, lines 40-50 and col. 4, lines 50-63); and said microprocessor is capable of writing to said means for receiving a plurality of first values and verifies correct functioning of the controller (col. 4, lines 50-63).

It would have been obvious to one having ordinary skill in the art at the time the invention was made to include the teaching of Ristic et al. in the system of Miller et al. in order to separate the environmental sensing devices from the microprocessor and

utilize said microprocessor to process data generated by said sensing devices and in turn allow control of power loads of the environment based on sensed signals (Ristic et al., col. 31-67).

Allowable Subject Matter

11. Claims 7, 8, 14, 15 and 18-27 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

Reasons for Allowance

12. The following is an examiner's statement of reasons for allowance:

The primary reason for the allowance of claims 7, 8, 14 and 15 is the inclusion of the limitation that said temperature measurement buffer is adapted to receive said first value by way of a single wire or a plurality of wires. It is this limitation found in each of the claims, as it is claimed in the combination, that has not been found, taught or suggested by the prior art of record which makes these claims allowable over the prior art.

The primary reason for the allowance of claims 18-27 is the inclusion of the limitation of a comparator response logic coupled to said comparator for determining whether an over-temperature condition in said integrated circuit exists. It is this limitation found in each of the claims, as it is claimed in the combination, that has not been found,

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taught or suggested by the prior art of record which makes these claims allowable over the prior art.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Response to Arguments

13. Applicant's arguments with respect to claims 1-5, 9, 11, 13, 16, 17, 29, 6, 10, 12, 28, 30-32, 35-38, 33 and 34 have been considered but are moot in view of the new ground(s) of rejection.

Claims 1, 2-5, 9, 11, 13, 16, 17, 29, 6, 10, 12, 28, 30-32, 35-38, 33 and 34 are rejected as new art (Miller et al., U.S. Pat. No. 6542846) has been found to teach a controller for monitoring a temperature of an integrated circuit that includes a comparator for comparing a first value received on a first interface with a second value received on a second interface to determine if the first interface value indicates an excessive temperature of an integrated circuit. For more detailed response, please refer to section 2 set forth above in this Office Action.

Contact Information

14. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Xiuqin Sun whose telephone number is (703)305-3467. The examiner can normally be reached on 7:00am-4:30pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, John Barlow can be reached on (703)308-3126. The fax phone numbers for the organization where this application or proceeding is assigned are (703)872-9306.

Xiuqin Sun Examiner Art Unit 2863

September 23, 2003

John Baffow Supervisory Palent Examiner Technology Center 2800